



<b>[FC2] Plasma &amp; Atomic Layer Etching II</b>	
<b>Date / Time</b>	July 27 (Fri.), 2018 / 13:40-15:00
<b>Place</b>	Room C (#114)
<b>Session Chair(s)</b>	Nam Hun Kim (Adaptive Plasma Tech. Corp., Korea) Thorsten Lill (Lam Research Corp., USA)

**FC2-1 [Invited] 13:40-14:10**

Atomic Layer Defect-Free Top-Down Processes for Future Nano-Devices

Seiji Samukawa

*Tohoku Univ., Japan*

**FC2-2 14:10-14:30**

Surface Reaction Mechanisms of Hexafluoroacetylacetone (HFAC) on a Nickel or Nickel Oxide Surface for Atomic-Layer Etching (ALE)

Abdulrahman Hikmat Basher<sup>1</sup>, Michiro Isobe<sup>1</sup>, Tomoko Ito<sup>1</sup>, Kazuhiro Karahashi<sup>1</sup>, Masato Kiuchi<sup>2</sup>, Takae Takeuchi<sup>3</sup>, and Satoshi Hamaguchi<sup>1</sup>

<sup>1</sup>*Osaka Univ., Japan*, <sup>2</sup>*AIST, Japan*, <sup>3</sup>*Nara Women's Univ., Japan*

**FC2-3 [Invited] 14:30-15:00**

Isotropic Atomic Layer Etching of ZnO on 2D and 3D Substrates Using Acetylacetone and O<sub>2</sub> Plasma

Alfredo Mamelì<sup>1</sup>, Marcel A. Verheijen<sup>1</sup>, Adrie J.M. Mackus<sup>1</sup>, Erwin (W.M.M.) Kessels<sup>1</sup>, and Fred Roozeboom<sup>1,2</sup>

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